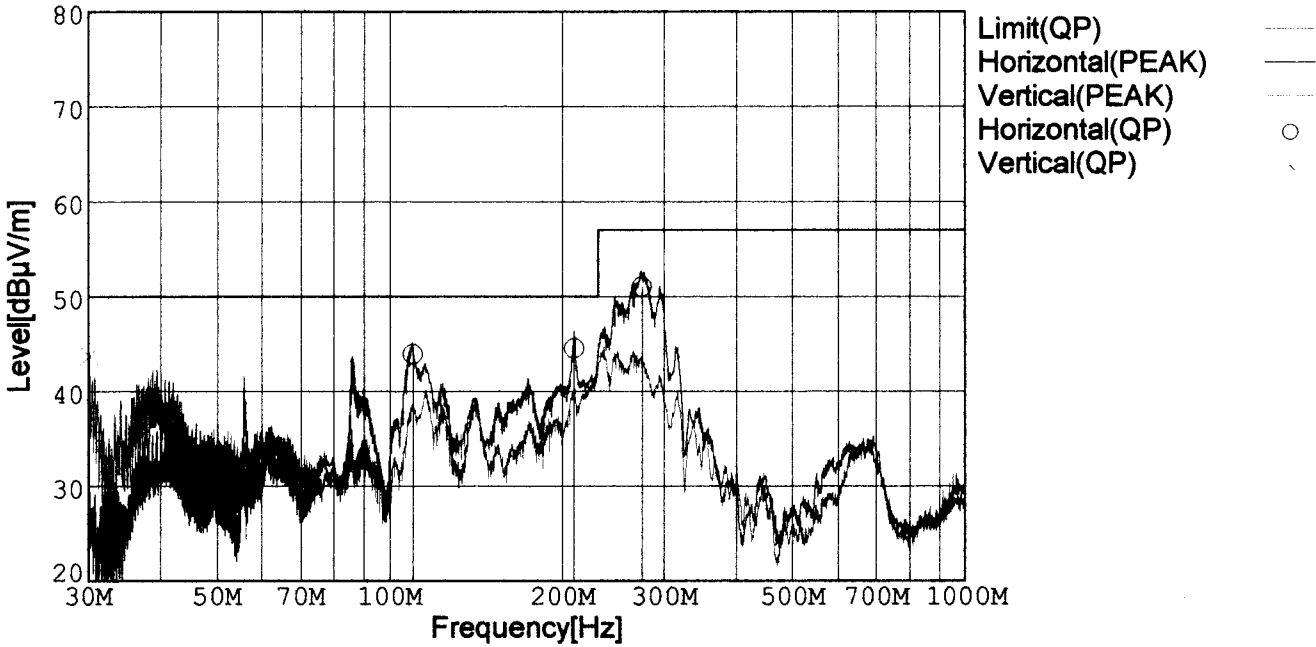




# RADIATED EMISSION

Model Name	: CDS6004828	Power Supply	: Vin=48V Vout=28V Iout=25A
Model No.	:	Temp.	: 25deg
Serial No.	:	Humi.	: 45%
Points	: 4	Date	: 2001/6/14 21:04
Detector	: PEAK/QP	Test Equip.	: R3132,ESPC
Polarization	: Hori. & Vert.	Tested by	: R.Sakai
Limit: [EN 55022] Class A<3m>			



Frequency [MHz]	Meter Reading (QP) [dBμV]	Ant. Type	Antenna Factor [dB/m]	Cable & Preamp [dB]	Level (QP) [dBμV/m]	Angle[°]	Height [cm]	Polar.	Limit [dBμV/m]	Margin [dB]
209.704	66.9	BL	8.7	-31.1	44.5	153	156	Hori.	50.0	5.5
274.602	69.5	BL	12.4	-30.9	51.0	302	109	Hori.	57.0	6.0
109.804	64.7	BL	10.7	-31.5	43.9	39	147	Hori.	50.0	6.1
30.106	57.6	BL	18.2	-32.1	43.7	177	100	Vert.	50.0	6.3

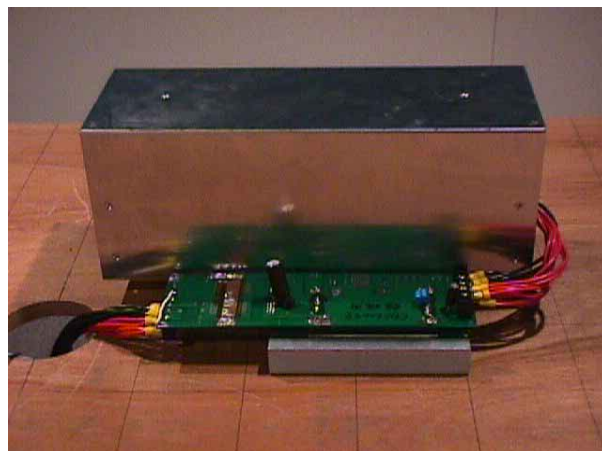
BL: Biconi-Log

# Conditions

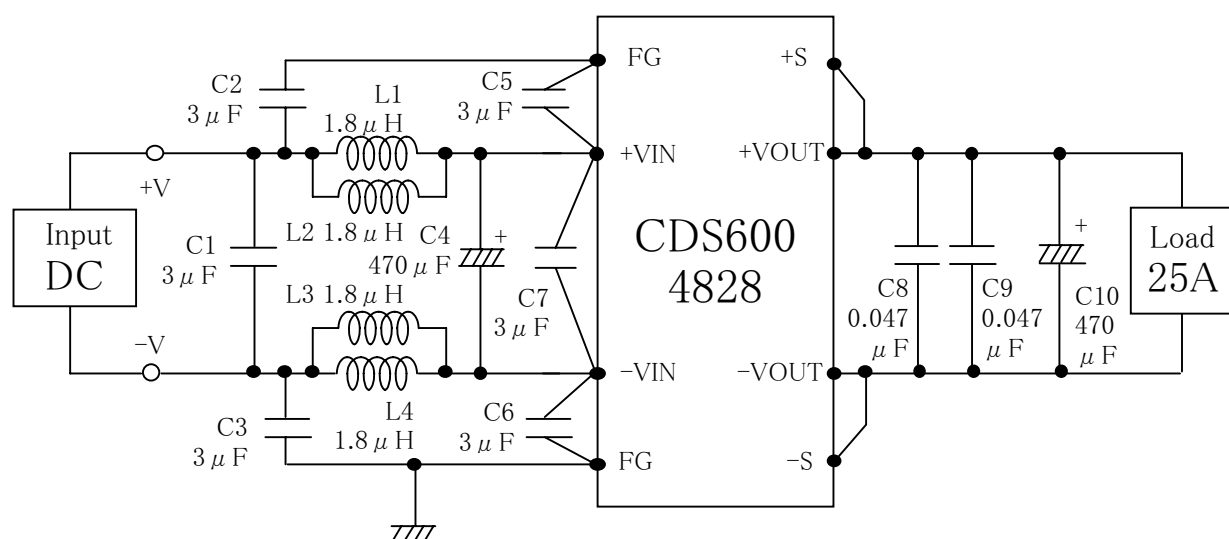
Date 2001/6/14

Test : RADIATED EMISSION  
Model Name : CDS6004828

## ○Photographs of Test Set-Up



## ○Testing circuitry



L1,L2,L3,L4 :ETQP6F1R8BFA(MATSUSHITA)  
C1,C2,C3,C5,C6,C7 :CY55Y5P2A305M(TOKIN)  
C4 :100V 470  $\mu$  F PFseries (nichicon)  
C8,C9 :MDS630V473K (Nitsuko)  
C10 :35V 470  $\mu$  F PWseries (nichicon)

Fig. Testing circuitry



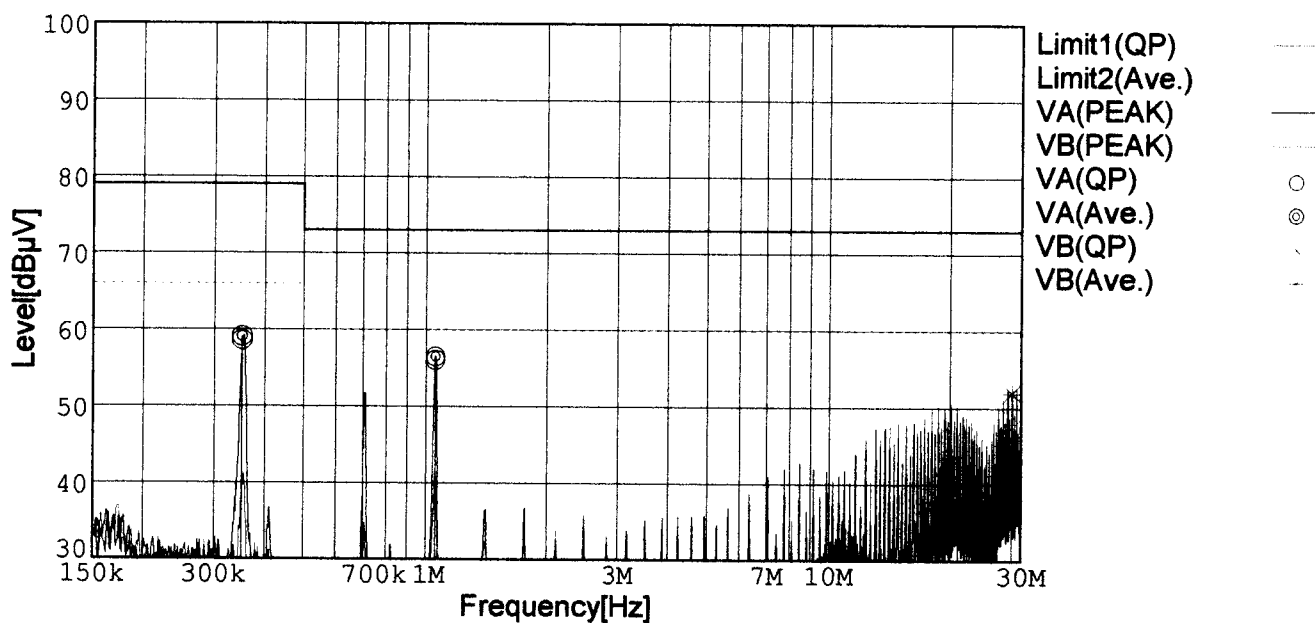
# LINE CONDUCTION

Model Name : CDS6004828  
 Model No. :  
 Serial No. :  
 Points : 3  
 Detector : PEAK/QP/Ave.  
 Line Mode : VA/VB

Power Supply : Vin=48V Vout=28V Iout=25A  
 Temp. : 25deg  
 Humi. : 45%  
 Date : 2001/6/12 22:40  
 Test Equip. : R3132,ESPC  
 Tested by : R.Sakai

Limit1: [EN 55022] Class A(QP)

Limit2: [EN 55022] Class A(Ave.)



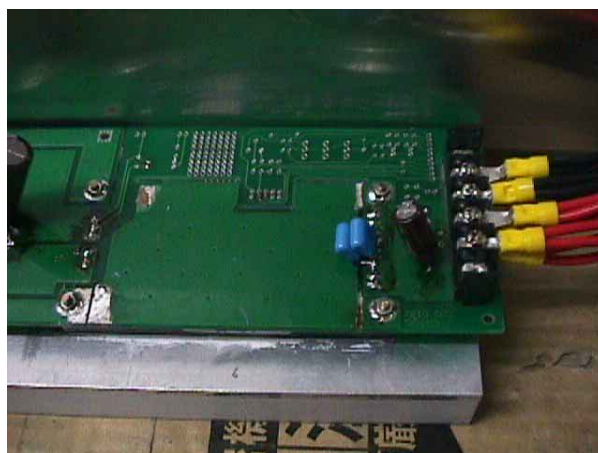
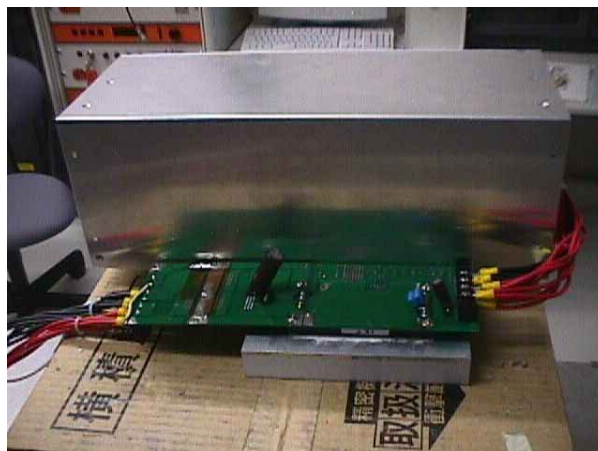
Frequency [MHz]	Meter Reading (QP) [dBμV]	Meter Reading (Ave.) [dBμV]	Factor [dB]	Level (QP) [dBμV]	Level (Ave.) [dBμV]	Line	Limit (QP) [dBμV]	Limit (Ave.) [dBμV]	Margin (QP)[dB]	Margin (Ave.) [dB]
0.3520	48.8	49.3	9.8	58.6	59.1	VA	79.0	66.0	20.4	6.9
1.0573	46.1	46.6	9.9	56.0	56.5	VA	73.0	60.0	17.0	3.5
28.5397	41.6	41.5	10.4	52.0	51.9	VB	73.0	60.0	21.0	8.1

# Conditions

Date 2001/6/12

Test : LINE CONDUCTION  
Model Name : CDS6004828

## Photographs of Test Set-Up



## Testing circuitry

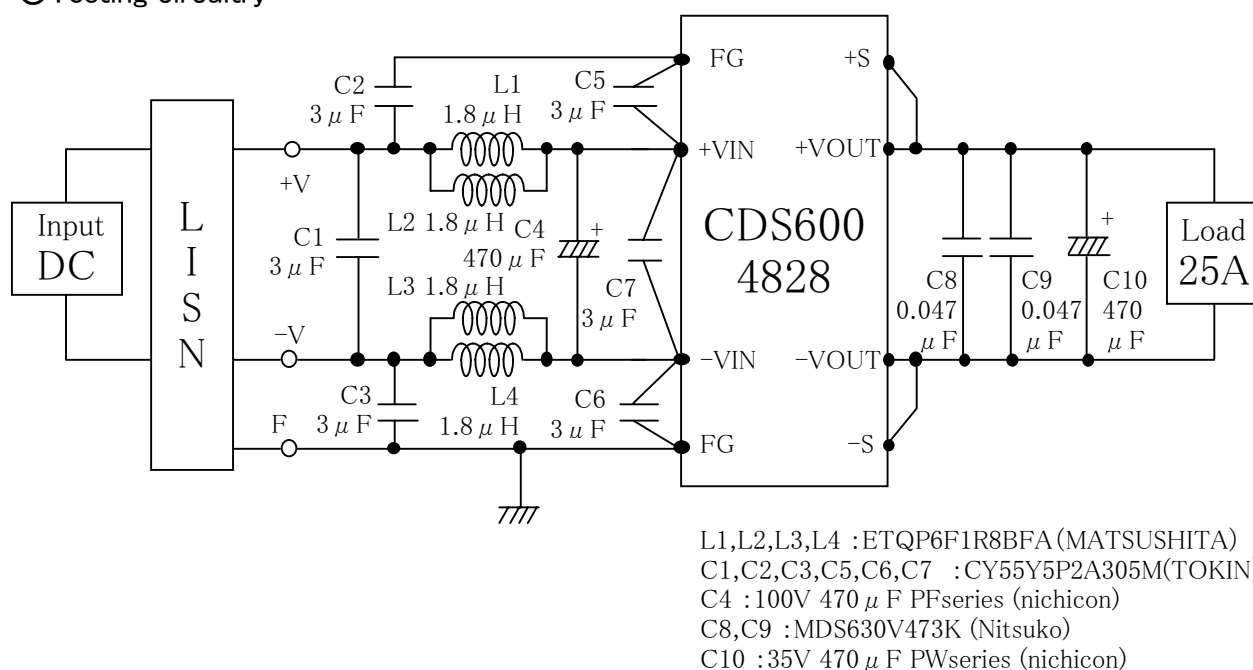


Fig. Testing circuitry